



Title of Change:	Release of T2000 tester platform for products NCV78763 (currently tested on Microflex).
Proposed Changed Material First Ship Date:	19 June 2018 <i>or earlier after customer approval</i>
Current Material Last Order Date:	15 July 2018 or earlier after customer approval Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.
Current Material Last Delivery Date:	15 July 2018 or earlier after customer approval The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory.
Product Category:	Active components – Integrated circuits
Contact information	Contact your local ON Semiconductor Sales Office, your Customer Quality Interface or <xavier.vanesch@onsemi.com>
Samples	No samples foreseen, unless requested by the customer. Contact your local ON Semiconductor Sales Office to place sample order. Sample requests are to be submitted no later than 45 days after publication of this change notification.
Sample Availability Date:	Not Applicable. No samples foreseen, unless requested by the customer.
PPAP Availability Date:	Not Applicable. No PPAP update foreseen.
Additional Reliability Data	Contact your local ON Semiconductor Sales Office, your Customer Quality Interface or <xavier.vanesch@onsemi.com>
Type of Notification	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 months prior to implementation of the change or earlier upon customer approval. ON Semiconductor will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 45 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.
Change Category:	Type of Change
Equipment	Change in final test equipment type that uses a different technology
Description and Purpose:	
Release of a second tester platform, T2000, for Final Test and QC to improve Test Capacity and Load Balancing	
No impact on the product itself (form, fit, function and reliability)	
Reason / Motivation for Change:	Improved Test Capacity and Load Balancing
Anticipated impact on fit, form, function, reliability, product safety or manufacturability	The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded. No anticipated impacts.
Sites Affected:	
☒ All site(s) ☐ not applicable ☐ ON Semiconductor site(s) : ☐ External Foundry/Subcon site(s)	

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**List of Affected Standard Parts:**

Current Part Number	New Part Number	Qualification Vehicle
NCV78763DQ0R2G	NCV78763DQ0R2G	NCV78763DQ0R2G
NCV78763DQ6R2G	NCV78763DQ6R2G	
NCV78763DQ0AR2G	NCV78763DQ0AR2G	
NCV78763DQ6AR2G	NCV78763DQ6AR2G	